

Data Sheet

January 2002

6.5A, 200V, 0.800 Ohm, P-Channel Power MOSFETs

These are P-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching converters, motor drivers, relay drivers and drivers for other high-power switching devices. The high input impedance allows these types to be operated directly from integrated circuits.

Formerly developmental type TA17512.

Ordering Information

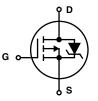
PART NUMBER	PART NUMBER PACKAGE BRAND			
IRF9630	TO-220AB	IRF9630		
RF1S9630SM	TO-263AB	RF1S9630		

NOTE: When ordering, use the entire part number. Add the suffix 9A to obtain the TO-263AB variant in the tape and reel, i.e., RF1S9630SM9A.

Features

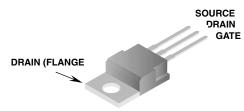
- 6.5A, 200V
- $r_{DS(ON)} = 0.800\Omega$
- Single Pulse Avalanche Energy Rated
- · SOA is Power Dissipation Limited
- · Nanosecond Switching Speeds
- Linear Transfer Characteristics
- · High Input Impedance
- · Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol

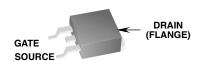


Packaging





JEDEC TO-263AB



IRF9630, RF1S9630SM

IRF9630.

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

1111 3000,	
RF1S9630SM	UNITS
-200	V
-200	V
-6.5	Α
-4	Α
-26	Α
±20	V
75	W
0.6	W/oC
500	mJ
-55 to 150	°C
300	°C
260	°C
	RF1S9630SM -200 -200 -6.5 -4 -26 ±20 75 0.6 500 -55 to 150

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = -250μA, V _{GS} = 0V(Figure 10)		-200	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = -250μA		-2	-	-4	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = Rated BV _{DSS} , V _{GS} = 0V		-	-	-25	μΑ
		V _{DS} = 0.8 x Rated BV _{DSS} ,	$V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	-250	μΑ
On-State Drain Current (Note 2)	I _{D(ON)}	V _{DS} > I _{D(ON)} x r _{DS(ON)MA}	(, V _{GS} = -10V	-6.5	-	-	Α
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V		-	-	°±±100	nA
On Resistance (Note 2)	r _{DS(ON)}	$I_D = -3.5A$, $V_{GS} = -10V$ (Fig	ures 8, 9)	-	0.500	0.800	Ω
Forward Transconductance (Note 2)	9fs	$V_{DS} \ge I_{D(ON)} \times r_{DS(ON)MAX}$, $I_{D} = -3.5A$ (Figure 12)		2.2	3.5	-	S
Turn-On Delay Time	t _{d(ON)}	$V_{DD} = -100V, I_{D} \approx -6.5A, R_{G} = 50\Omega$		-	30	50	ns
Rise Time	t _r	$R_L = 15.4\Omega$ (Figures 17, 18)		-	50	100	ns
Turn-Off Delay Time	t _{d(off)}	MOSFET Switching Times are Essentially Independent of Operating Temperature		-	50	100	ns
Fall Time	t _f			-	40	80	ns
Total Gate Charge (Gate to Source + Gate to Drain)	Q _{g(TOT)}	V _{GS} = -10V, I _D = -6.5A, V _{DS} = 0.8 x Rated BV _{DSS} I _{g(REF)} = -1.5mA (Figures 14, 19, 20) Gate Charge is Essentially Independent of Operating Temperature		-	31	45	nC
Gate to Source Charge	Q _{gs}			-	18	-	nC
Gate to Drain ("Miller") Charge	Q _{gd}			-	13	-	nC
Input Capacitance	C _{ISS}	V_{DS} = -25V, V_{GS} = 0V, f = 1MHz (Figure 11)		-	550	-	pF
Output Capacitance	Coss			-	170	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	50	-	pF
Internal Drain Inductance	L _D	Measured From the Contact Screw On Tab To the Center of Die	n Tab To Symbol Showing the Internal Devices Inductances OD OD OD OD OD OD OD OD OD O	-	3.5	-	nΗ
		Measured From the Drain Lead, 6mm (0.25in) From Package to the Center of Die		-	4.5	-	nH
Internal Source Inductance	L _S	Measured From the Source Lead, 6mm (0.25in) From Package to Source Bond- ing Pad	G ELS	-	7.5	-	nH
Thermal Resistance Junction to Case	$R_{\theta JC}$			-	-	1.67	°C/W
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Typical Socket Mount		-	-	80	°C/W

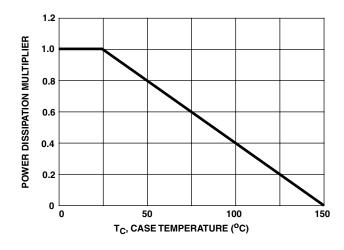
Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		TYP	MAX	UNITS
Continuous Source to Drain Current	I _{SD}	Modified MOSFET Symbol		-	-6.5	А
Pulse Source to Drain Current (Note 3)	^I SDM	Showing the Integral Reverse P-N Junction Diode)	-	-26	A
Source to Drain Diode Voltage (Note 2)	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = -6.5A$, $V_{GS} = 0V$ (Figure 13)		-	-1.5	V
Reverse Recovery Time	t _{rr}	$T_J = 150^{\circ}C$, $I_{SD} = -6.5A$, $dI_{SD}/dt = 100A/\mu s$		400	-	ns
Reverse Recovery Charge	Q_{RR}	$T_J = 150^{\circ}$ C, $I_{SD} = -6.5$ A, $dI_{SD}/dt = 100$ A/ μ s		2.6	-	μС

NOTES:

- 2. Pulse Test: Pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
- 3. Repetitive Rating: Pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4. $V_{DD} = 50V$, starting $T_J = 25^{\circ}C$, L = 17.75mH, $R_G = 25\Omega$, peak $I_{AS} = 6.5$ A. (Figures 15, 16).

Typical Performance Curves Unless Otherwise Specified



-10
(e) -8
(f) -8
(h) -9
(h) -

FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

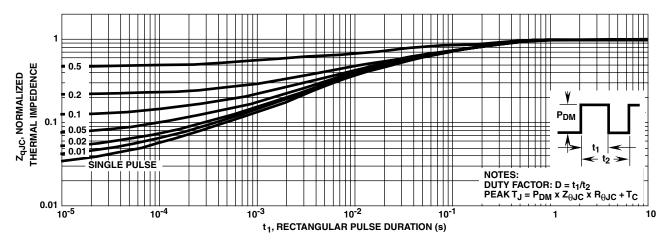


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves Unless Otherwise Specified (Continued)

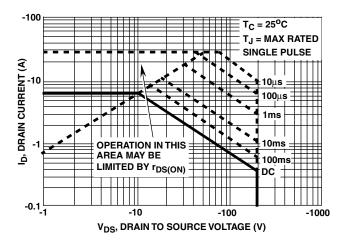


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

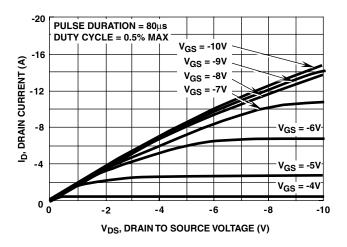
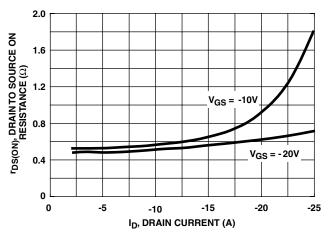


FIGURE 6. SATURATION CHARACTERISTICS



NOTE: Heating effect of 2µs pulse is minimal.

FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

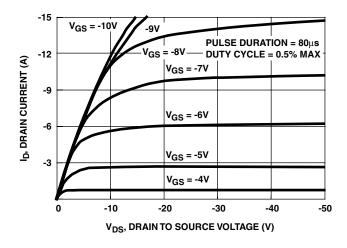


FIGURE 5. OUTPUT CHARACTERISTICS

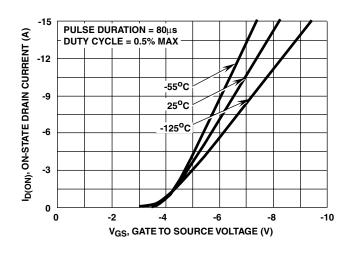


FIGURE 7. TRANSFER CHARACTERISTICS

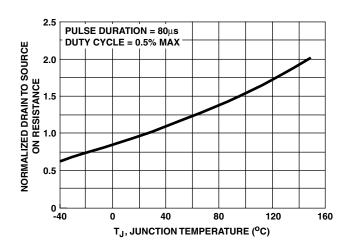
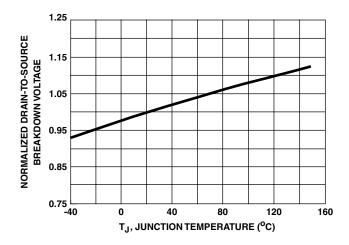


FIGURE 9. NORMALIZED DRAINTO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

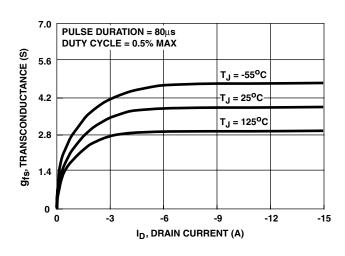
Typical Performance Curves Unless Otherwise Specified (Continued)



2000 V_{GS} = 0V, f = 1MHz C_{ISS} = C_{GS} + C_{GD} C_{RSS} = C_{GD} 1600 $C_{OSS} \approx C_{DS} + C_{GD}$ C, CAPACITANCE (pF) 1200 CISS 800 Coss 400 CRSS 0 0 10 20 30 40 50 V_{DS}, DRAIN TO SOURCE VOLTAGE (V)

FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



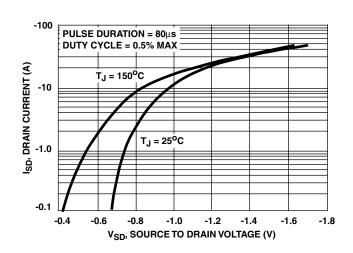


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

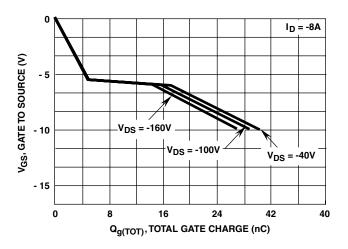


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

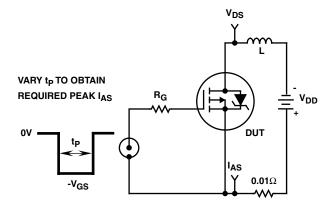


FIGURE 15. UNCLAMPED INDUCTIVE ENERGY TEST CIRCUIT

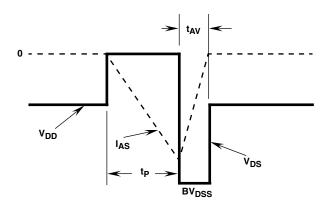


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

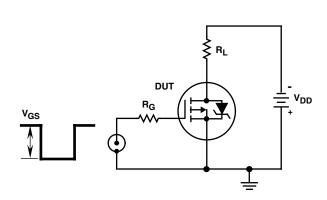


FIGURE 17. SWITCHING TIME TEST CIRCUIT

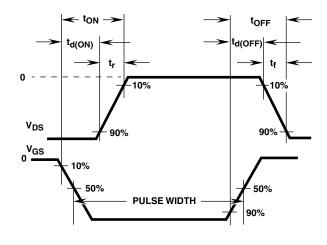


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

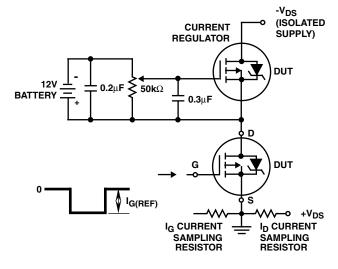


FIGURE 19. GATE CHARGE TEST CIRCUIT

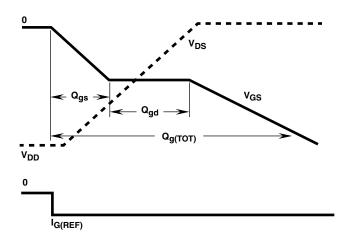


FIGURE 20. GATE CHARGE WAVEFORMS

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